

Figure 1

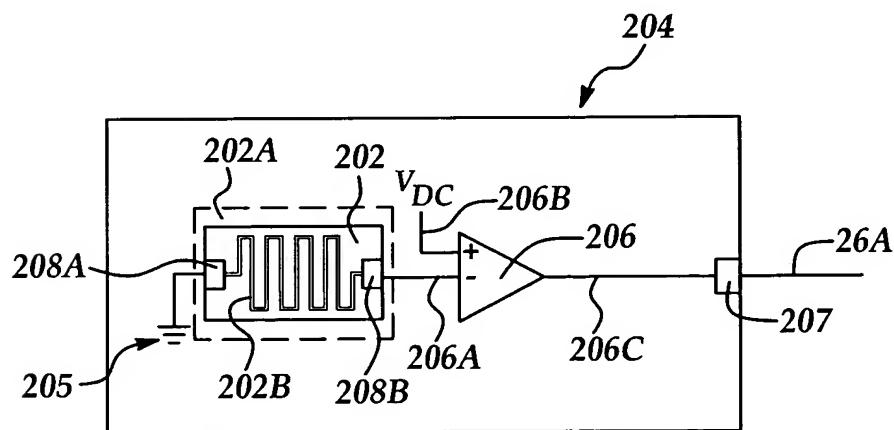


Figure 2A



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202 REPLACEMENT SHEET

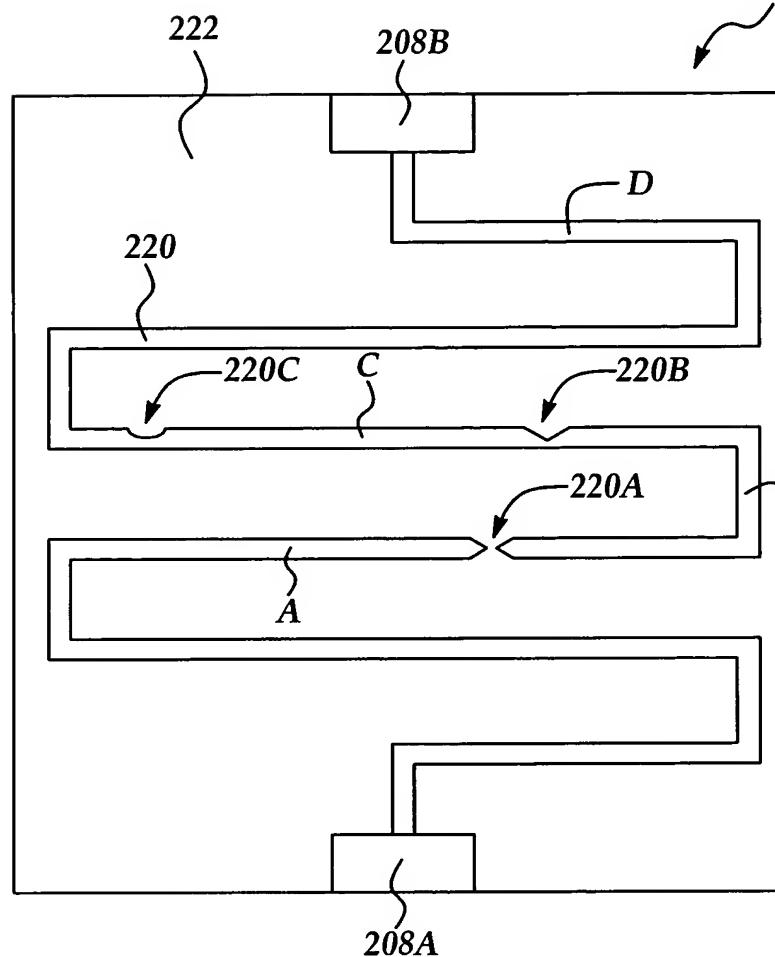


Figure 2B

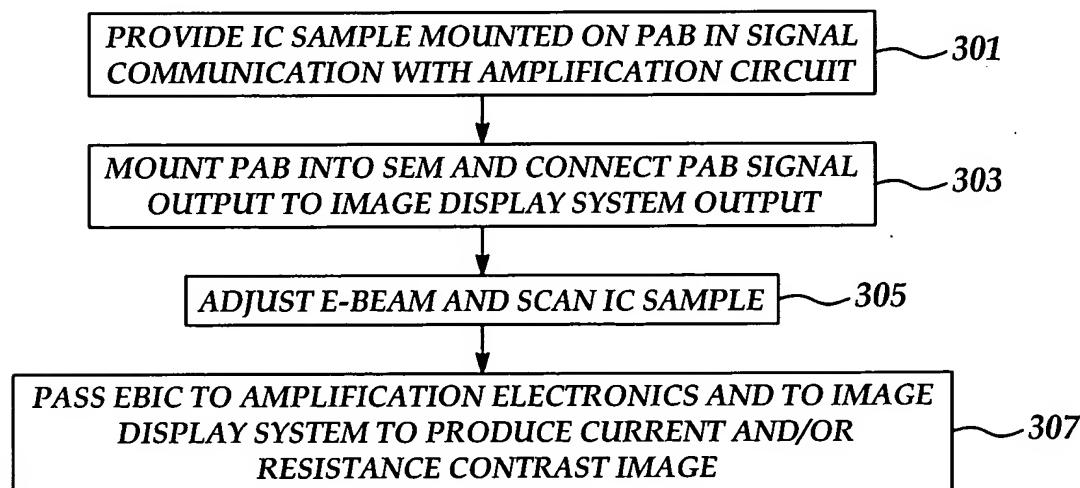


Figure 3